

U.S. DEPARTMENT OF COMMERCE

PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S)

(Use several sheets if necessary)

Date Submitted to PTO: October 23, 2001

ATTY DOCKET NO.

862.C2171

APPLICATION NO.

09/819,672

APPLICANT

Takayuki YAGI, et al.

FILING DATE

March 29, 2001

GROUP

2878

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
EN	5,834,783	11/10/1998	Muraki, et al.	250	398	
	5,864,142	01/26/1999	Muraki, et al.	250	491.1	
	5,905,267	05/18/1999	Muraki	250	492.22	
	5,981,954	11/09/1999	Muraki	250	397	
	6,107,636	08/22/2000	Muraki	250	492.2	
	6,104,035	08/15/2000	Muraki	250	492.22	
	6,166,387	12/26/2000	Muraki, et al.	250	492.2	
	5,929,454	07/27/1999	Muraki, et al.	250	491.1	
	5,939,725	08/17/1999	Muraki	250	492.22	
	5,973,332	10/26/1999	Muraki, et al.	250	492.2	
	6,137,113	10/24/2000	Muraki	250	492.22	
EN	4,419,580	12/06/1983	Walker, et al.	250	396 R	

## FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

E. MU YEN

DATE CONSIDERED

02-28-03

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.

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Sheet 1 of 2

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE  
LIST OF REFERENCES CITED BY APPLICANT(S)(Use several sheets if necessary)  
Date Submitted to PTO: October 23, 2001ATTY DOCKET NO.  
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**2878**

## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

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## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

len	"Sub-Nanometer Miniature Electron Microscope", A.D. Feinerman, et al., Journal of Vacuum Science and Technology A, Vol. 10, No. 4, July/August 1992, 611-616.
len	"High Aspect Ratio Aligned Multilayer Microstructure Fabrication", K. Y. Lee, et al., Journal of Vacuum Science and Technology B, Vol. 12, No. 6, November/December 1994, pp. 3425-3430.
ten	"Arrayed Miniature Electron Beam Columns For High Throughput Sub-100 nm Lithography", T. H. P. Chang, et al., Journal of Vacuum Science and Technology B, Vol. 10, No. 6, November/December 1992, pp. 2743-2748.
len	"Microstructures for Particle Beam Control", G. W. Jones, et al., Journal of Vacuum Science and Technology B, Vol. 6, No. 6, November/December 1988, pp. 2023-2027.
len	"A Multibeam Scheme for Electron-Beam Lithography", T. Sasaki, Journal of Vacuum Science and Technology, Vol. 19, No. 4, November/December 1981, pp. 963-965.

EXAMINER

len. MUYEN

DATE CONSIDERED

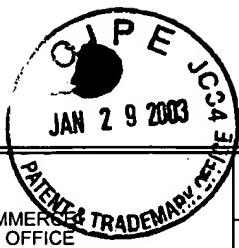
028-28-03

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Sheet 2 of 2



FORM PTO 1449 (modified)

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PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)

January 29, 2003

ATTY DOCKET NO. 00862.022171

APPLICATION NO. 09/819,672

APPLICANT Takayuki YAGI et al.

FILING DATE March 29, 2001

GROUP 2878

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
EN	5,121,234	06/09/1992	Kucera	359	50	
EN	5,604,394	02/18/1997	Saito et al.	313	422	
EN	6,381,702	04/30/2002	Ogasawara	713	500	
	<del>2002/0051111</del>	<del>05/02/2002</del>	<del>Greene et al.</del>	<del>349</del>	<del>149</del>	
↳ this is not considered as the prior art.						

## FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER  k. MUYEN	DATE CONSIDERED  02-28-03
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